



A Compact Coded-mask Imaging Camera with a CdTe Double-sided Strip Detector

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Wide FOV Gamma-ray Camara for Space

Astronomical objects are often "highly" variable in X-ray and Gamma-ray. In order to monitor these sources and to study their nature, **An All Sky Monitor is important**.





 With a wide FOV coded-mask, Swift and Integral have provided spectral and temporal information of MANY hard X-ray sources.
Identification of these Hard X-ray Sources contributes greatly to our understanding of radiation mechanism of these sources.



- Our approach :
 - Small size coded mask module
 - Multiple modules : Sensitivity and FoV scalable
 - Background rejection with anti coincidence shields
 - Small satellite
 - Low cost
 - Variety of use

Difficulty : Keeping required angular resolution (~10 arcmin), when solution (when solution the imaging system.



How to make the imager smaller

Factors for angular resolution :



CdTe Double-side Strip Detector

KEY TECHNOLOGY Developed by ISAS/JAXA (ex. Watanabe et al. (2009))

- CdTe Double-side Strip Detector (CdTe DSD)
 - Strip pitch : 250 μm
 - Number of strips : 128 x 128 ch (16384 pixel)
 - Detector size : $32 \times 32 \text{ mm}^2$
- thickness : 750 μ m
- Based on CdTe "Schottky" Diode (Takahashi et al. 1998)



Energy Resolution



Imaging Capability



Compact Coded Mask Detector

KEY TECHNOLOGY : Micro Coded Mask



a newly developed fine aperture coded mask

- Coded aperture : $350 \mu m$
- Mask size : 36.75 x 36.75 mm²
- Mask thickness : ~ 400 μ m
- 8 stacks of Ni (50 μ m) plated Au (2-3 μ m)
- transparency
 - :0%~30 keV, 50% @60 keV, 75%@120 keV
- Random Mask, mask open fraction 0.5
- Extracted from the pattern used in Swift/BAT



Experimental Setup



- Cooling System using Peltier
- Image deconvolution method : Balanced Correlation Method





Performance Evaluation



Linearity in sky image

40

30

Obs. 80 min, -5°C

Factors for degrading image linearity :

- Non-unifomity of focal detector
- Polarization effect of CdTe <u>Am#1 3360 kBq</u>



Result is well consistent with the expected value.

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100

Imaging capability in hard X-ray

Experimental results with ²⁴¹Am (17, 59 keV) and ⁵⁷Co (122 keV)



Imaging up to ~ 120 keV is achieved.

In high energy region, the coded mask becomes transparency. Although a thick mask can expand energy band, it makes the field of view narrow. **Tradeoff studies and optimization are underway**.

Development of MC simulator

Studies for astrophysical use

Optimization of mask and detector configuration

Reduction of systematic error







Next work

mm

Design optimized for astrophysical use

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X [mm]

²⁴¹Am, 17 keV (Experiment)

Summary

We have developed a new "Compact" imager for hard X-rays (10 - 100 keV) based on newly developed

1. Large area (~ 10 cm²) and high resolution (~ a few hundred μ m) CdTe Imagers —— CdTe Double Sided Detector

2. Fine pitch coded masks

The performance of the first prototype is very promising to realize an instrument to be onboard a future mission.

Angular resolution : ~ 10 - 15 arcmin Energy range : 5 - 150 keV Reasonable Sensitivity and All sky coverage by using multiple units with Narrow FOV + Shield



Thank you !!



Simple Sensitivity Calculation for a future mission

	Swift/BAT	Our prototype	Figure of Merit = FoV x Area
FoV [deg	4600	256	With 18 units, can cover the same FoV
Detector Area [cm	5200	10.24	With 18x28 units, can achieve the same area

